

ISSUE CLASSIFICATION	
Class	Subclass

U.S. UTILITY Patent Application

AK SCANNED	Q.I.P.E. Q.A.	PATENT DATE
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APPLICATION NO. 09/708490	CONT/PRIORS F	CLASS 400 702	SUBCLASS INT 85	ART UNIT 2812 2863	EXAMINER LAC
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TITLE: APPLICANTS

Chief Iwasa

Semiconductor testing method and semiconductor testing apparatus for semiconductor devices, and program for executing semiconductor testing method

PTO-2040
12/99

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ISSUING CLASSIFICATION												
ORIGINAL				CROSS REFERENCE(S)								
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
INTERNATIONAL CLASSIFICATION												

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drawg	Figs. Drawg	Print Fig.	Total Claims	Print Claim for O/G
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.	_____ (Assistant Examiner) (Date)			NOTICE OF ALLOWANCE MAILED	
	<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent No. _____	_____ (Primary Examiner) (Date)			ISSUE FEE
Amount Due					Date Paid
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	_____ (Legal Instruments Examiner) (Date)			ISSUE BATCH NUMBER	

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